

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: A. Bhavnagarwala et al.

Examiner: West, Jeffrey R.

Serial No.: 10/643,193

Group: Art Unit 2857

Filed: August 18, 2003

Docket: YOR920030289US1 (8728-635)

For:

**CIRCUITS AND METHODS FOR CHARACTERIZING
RANDOM VARIATIONS IN DEVICE CHARACTERISTICS
IN SEMICONDUCTOR INTEGRATED CIRCUITS**

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313

AMENDMENT

This is a response to the Office Action mailed on July 26, 2006. Please amend the application as follows: